



IEC QUALITY ASSESSMENT SYSTEM (IECQ)
covering Electronic Components,
Assemblies, Related Materials and Processes
For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.:	IECQ-L ULTW 16.0003-02	Issue No.:	6	Status:	Current
Additional Site to Certification: IECQ-L ULTW 16.0003 Originally Issued: 2016/07/28					
Supersedes:	IECQ-L ULTW 16.0003-02 Issue 5		Issue Date:	2023/08/15	Site Added: 2016/07/28
CB Reference No.:	20002490 ITL		Expiration:	2025/07/27	

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The organization, facilities and procedures have been assessed and found to comply with the applicable requirements for Independent Testing Laboratory organization approval, in support of the IECQ system, which is in accordance with the Basic Rules IECQ 01 and Rules of Procedure IECQ 03-6 "Independent Testing Laboratory Assessment Program Requirements" of the IEC Quality Assessment System for Electronic Components (IECQ) and applicable requirements of ISO/IEC 17025:2017 for the testing of electronic components under the IECQ.

Scope:
The materials analysis, chemical analysis and failure analysis of semiconductors.
See attached Schedule.

-- Attached Schedule: IECQ-L_ULTW_20002490 ITL, 08-15-23.pdf --

Approved by Certification Body (CB): DQS Group - DQS Taiwan Inc.

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Feng Yuan Dist., Taichung City
Taiwan

Authorized person:
Rock Chang



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.
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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-02

CB Certificate No.: 20002490 ITL

Schedule Number: IECQ-L ULTW 16.0003-02-S Rev No.: 6 Revision Date: 2023/08/15 Page 1 of 1

Appendix-1 (20002490 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Energy Dispersive Spectrometry of X-ray (EDS)	T-SEM-3, T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
X-Ray imaging	T-EFA-3
Emission Microscopy (EMMI)	T-EFA-3
Emission Microscopy (EMMI)-InGaAs	T-EFA-3
Optical Beam Induced Resistance Change (OBIRCH)	T-EFA-3
Scanning Acoustic Tomography (SAT)	T-EFA-3
Optical Microscope (OM)	T-OMI-3
3D Optical Microscope (3D OM)	T-LAB-3
IC Layout Imaging	T-OMI-3
Circuitry analysis	T-OMI-3
Thermal Emission Microscope (THEMOS)	T-EFA-3

Technical Reviewer of DQS: Michael Chou Date: 8/15/2023

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